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## **SAR Evaluation Report**

Application No.: SZEM1701000241CR

Applicant: Gibson Innovations Limited Manufacturer: Gibson Innovations Limited Factory: Minami Acoustics Limited **Product Name:** Bluetooth Headphones

"SHB3075, SHB3075YY/XX, SHB3075BK/27, SHB3075WT/27, SHB3075RD/27, SHB3075BL/27" (X = 0 to 9, Y = A to Z for marketing purpose) Model No.(EUT):

Please refer to section 2 of this report which indicates which model was actually

tested and which were electrically identical.

Trade Mark: **Philips** 

2AANUSHB3075 FCC ID:

Standards: 47 CFR Part 1.1307 (2016)

47 CFR Part 2.1093 (2016)

KDB447498D01 General RF Exposure Guidance v06

Date of Receipt: 2017-01-10

Date of Test: 2017-01-11 to 2017-01-14

Date of Issue: 2017-01-18

Test Result: PASS\*

#### Authorized Signature:



Jack Zhang **EMC Laboratory Manager** 

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing

The report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the federal government. All test results in this report can be traceable to National or International Standards.

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In the configuration tested, the EUT complied with the standards specified above.



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## 2 Version

Revision Record					
Version	Chapter	Date	Modifier	Remark	
01		2017-01-18		Original	

Authorized for issue by:		
Tested By	Brir Chen	2017-01-14
	(Bill Chen) /Project Engineer	Date
Checked By	Eric Fu	2017-01-18
	(Eric Fu) /Reviewer	Date



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### 4 General Information

#### 4.1 Client Information

Applicant:	Gibson Innovations Limited
Address of Applicant:	5/F, Philips Electronics Building, 5 Science Part East Avenue, Hong Kong Science Park, Shatin, N.T. Hong Kong
Manufacturer:	Gibson Innovations Limited
Address of Manufacturer:	5/F, Philips Electronics Building, 5 Science Part East Avenue, Hong Kong Science Park, Shatin, N.T. Hong Kong
Factory:	Minami Acoustics Limited
Address of Factory:	NO.13, Maonan Road, Torch Development District, Zhongshan City, Guangdong Province, China.

## 4.2 General Description of EUT

Product Name:	Bluetooth Headphones
Model No.:	SHB3075
Trade Mark:	Philips
Operation Frequency:	2402MHz~2480MHz
Modulation Type:	GFSK, π/4DQPSK, 8DPSK
Number of Channel:	79
Hopping Channel Type:	Adaptive Frequency Hopping systems
Sample Type:	Portable production
Antenna Type:	Integral
Antenna Gain:	0dBi
Power Supply:	Internal rechargeable battery: DC 3.7V 240mAh
	Charge by USB DC 5V
Test Voltage:	AC 120V 60Hz
Cable:	USB cable: 50cm unshielded

#### Remark:

Model No.: "SHB3075, SHB3075YY/XX, SHB3075BK/27, SHB3075WT/27, SHB3075RD/27, SHB3075BL/27" (X = 0 to 9, Y = A to Z for marketing purpose)

Only the model SHB3075 was tested, since the electrical circuit design, layout, components used and internal wiring were identical for the above models, only different on model name and color



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#### 4.3 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch

No. 1 Workshop, M-10, Middle section, Science & Technology Park, Shenzhen, Guangdong, China 518057

Telephone: +86 (0) 755 2601 2053 Fax: +86 (0) 755 2671 0594

No tests were sub-contracted.

### 4.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

#### • CNAS (No. CNAS L2929)

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

#### • A2LA (Certificate No. 3816.01)

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 3816.01.

#### VCCI

The 10m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-823, R-4188, T-1153 and C-2383 respectively.

#### • FCC - Registration No.: 556682

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 556682.

#### Industry Canada (IC)

Two 3m Semi-anechoic chambers and the 10m Semi-anechoic chamber of SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab have been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1, 4620C-2, 4620C-3.

#### 4.5 Deviation from Standards

None.

#### 4.6 Abnormalities from Standard Conditions

None.

## 4.7 Other Information Requested by the Customer

None.



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#### 5 SAR Evaluation

## 5.1 RF Exposure Compliance Requirement

#### 5.1.1 Standard Requirement

According to KDB447498D01 General RF Exposure Guidance v06

4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

#### **5.1.2 Limits**

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]  $\cdot [\sqrt{f(GHz)}] \le 3.0$  for 1-g SAR and  $\le 7.5$  for 10-g extremity SAR, where

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation 17

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is  $\leq$  50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion

#### 5.1.3 EUT RF Exposure

The Max Conducted Peak Output Power is 4.03dBm in middle channel(2.441GHz);

4.03dBm logarithmic terms convert to numeric result is nearly 2.53mW

According to the formula. calculate the test exclusion thresholds:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] · [\( \sqrt{f(GHz)} \)]

General RF Exposure =  $(2.53 \text{mW} / 5 \text{ mm}) \times \sqrt{2.441 \text{GHz}} = 0.79 \text{ }\bigcirc$ 

SAR requirement:

S= 3.0 ②;

(1) < (2).

So the SAR report is not required.